Device Modeling Report

COMPONENTS: BIPOLAR JUNCTION TRANSISTOR PART NUMBER: 2SC3467D_25C MANUFACTURER: SANYO

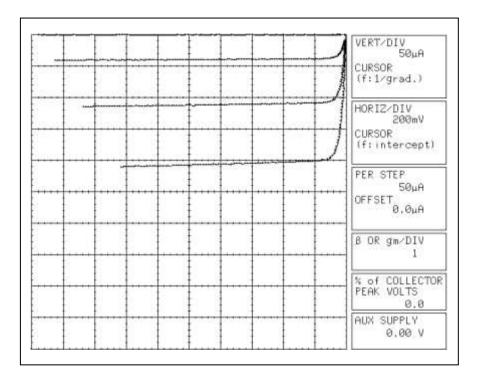


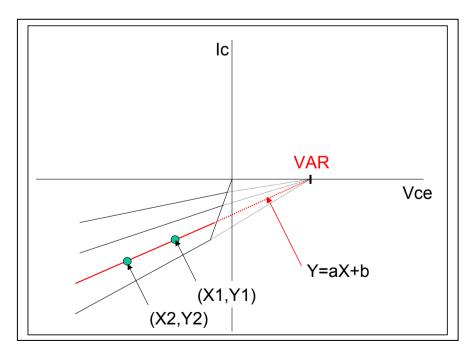
Bee Technologies Inc.

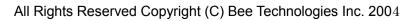
Pspice model parameter	Model description			
IS	Saturation Current			
BF	Ideal Maximum Forward Beta			
NF	Forward Current Emission Coefficient			
VAF	Forward Early Voltage			
IKF	Forward Beta Roll-off Knee Current			
ISE	Non-ideal Base-Emitter Diode Saturation Current			
NE	Non-ideal Base-Emitter Diode Emission Coefficient			
BR	Ideal Maximum Reverse Beta			
NR	Reverse Emission Coefficient			
VAR	Reverse Early Voltage			
IKR	Reverse Beta Roll-off Knee Current			
ISC	Non-ideal Base-Collector Diode Saturation Current			
NC	Non-ideal Base-Collector Diode Emission Coefficient			
NK	Forward Beta Roll-off Slope Exponent			
RE	Emitter Resistance			
RB	Base Resistance			
RC	Series Collector Resistance			
CJE	Zero-bias Emitter-Base Junction Capacitance			
VJE	Emitter-Base Junction Potential			
MJE	Emitter-Base Junction Grading Coefficient			
CJC	Zero-bias Collector-Base Junction Capacitance			
VJC	Collector-base Junction Potential			
MJC	Collector-base Junction Grading Coefficient			
FC	Coefficient for Onset of Forward-bias Depletion			
	Capacitance			
TF	Forward Transit Time			
XTF	Coefficient for TF Dependency on Vce			
VTF	Voltage for TF Dependency on Vce			
ITF	Current for TF Dependency on Ic			
PTF	Excess Phase at f=1/2pi*TF			
TR	Reverse Transit Time			
EG	Activation Energy			
XTB	Forward Beta Temperature Coefficient			
XTI	Temperature Coefficient for IS			

Reverse

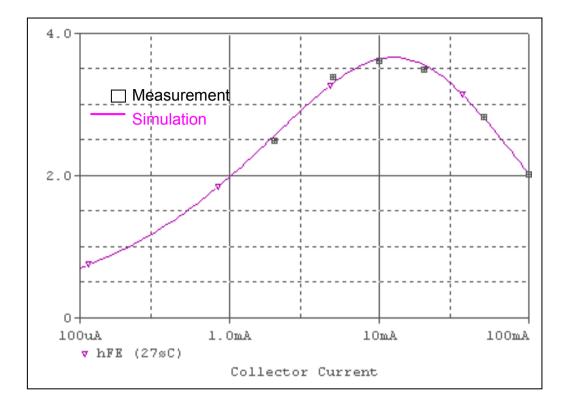
Reverse Early Voltage Characteristic





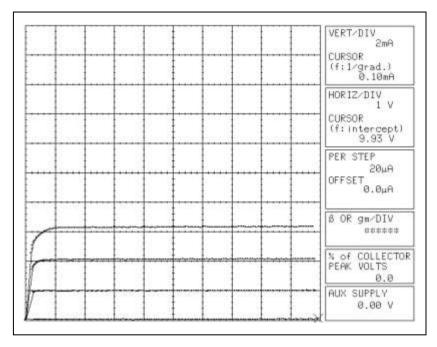


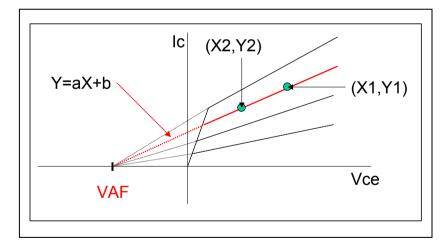
Reverse DC Beta Characteristic (le vs. hfe)

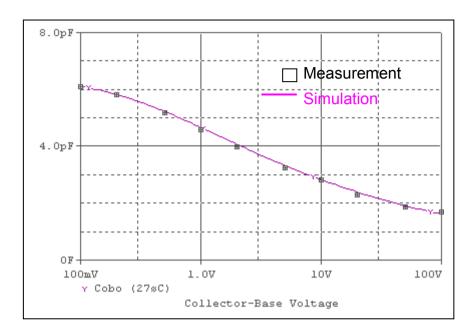


Forward

Forward Early Voltage Characteristic

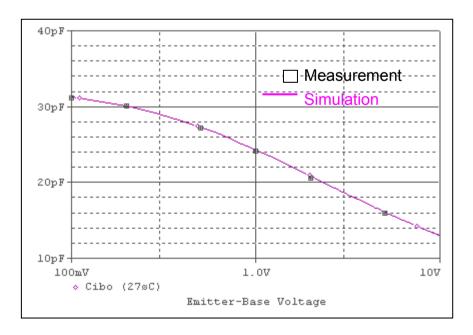




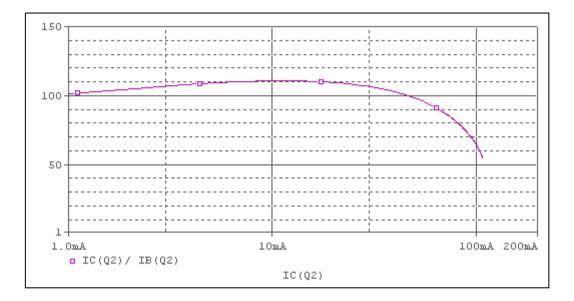


C-B Capacitance Characteristic

E-B Capacitance Characteristic

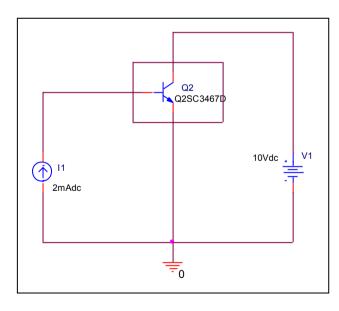


BJT Ic-hfe characteristics



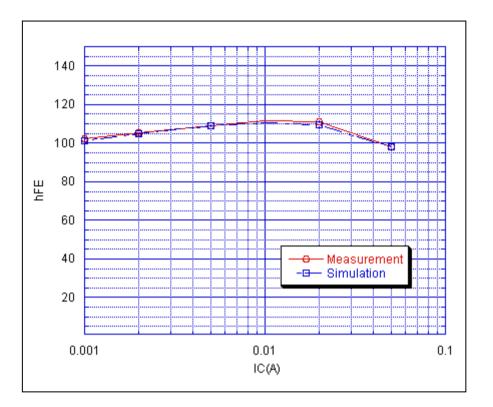
Circuit simulation result

Evaluation circuit



Comparison Graph

Circuit simulation result

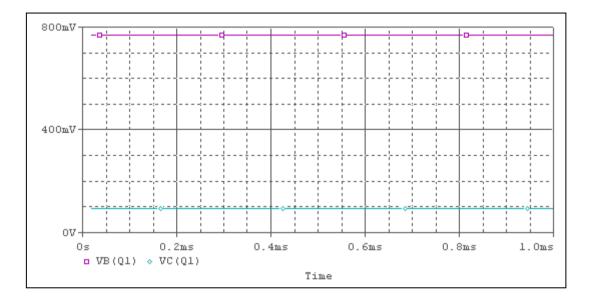


Simulation result

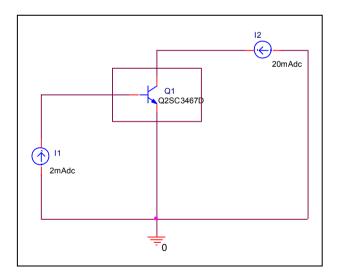
	hFE		%Error	
lc(A)	Measurement	Simulation	70E1101	
0.001	102.04	100.98	1.03880831	
0.002	105.2	104.98	0.209125475	
0.005	109.17	109.11	0.054960154	
0.01	111.85	110.61	1.108627626	
0.02	110.94	109.68	1.135749054	
0.05	98	98.1	0.102040816	

BJT Vce(sat) voltage & Vbe(sat) voltage Characteristics

Circuit simulation result



Evaluation circuit



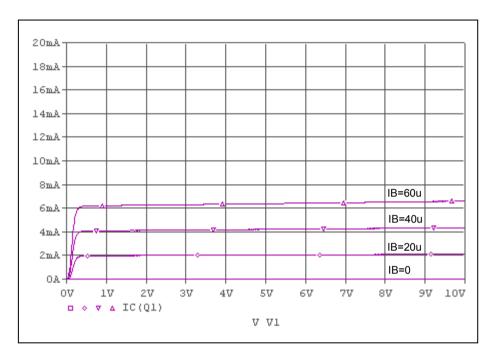
Simulation result

Test condition: IC/IB = 10, IC=20mA

Vce(sat)(V)			Vbe(sat)(V)		
Measurement	Simulation	Error(%)	Measurement	Simulation	Error(%)
600m[max]	92.86m	-	1000m[max]	769.9m	-

Output Characteristics

Circuit simulation result



Evaluation circuit

